

SEMI-AUTOMATIC PROBER

ABSTRACT

5 A wafer probe station system for reliability testing of a semiconductor wafer.
The wafer probe station is capable of interfacing with interchangeable modules for
testing of semiconductor wafers. The wafer probe station can be used with different
interchangeable modules for wafer testing. Modules, such as probe card positioners
and air-cooled rail systems, for example, can be mounted or docked to the probe
10 station. The wafer probe station is also provided with a front loading mechanism
having a rotatable arm that rotates at least partially out of the probe station
chamber for wafer loading.

FIG. 2B

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